

# SEMiX355MLI12M7



SEMiX® 5

## 3-Level NPC IGBT-Module

### SEMiX355MLI12M7

#### Features\*

- Solderless assembling solution with PressFIT signal pins and screw power terminals
- Trenchgate Technology
- $V_{CE(sat)}$  with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and reliable internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

#### Typical Applications

- UPS
- Solar

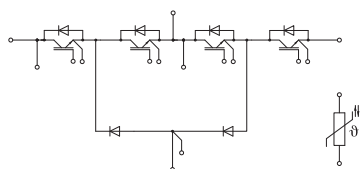
#### Remarks\*

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
- Product reliability results valid for  $T_j \leq 150^\circ\text{C}$  (recommended  $T_{j,op} = -40 \dots +150^\circ\text{C}$ )
- IGBT1: outer IGBTs T1 & T4
- IGBT2: inner IGBTs T2 & T3
- Diode1: outer diodes D1 & D4
- Diode2: inner diodes D2 & D3
- Diode5: clamping diodes D5 & D6
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"

#### Footnotes

<sup>1)</sup> Please find further technical information on the SEMIKRON website.

Absolute Maximum Ratings				
Symbol	Conditions	Values	Unit	
<b>IGBT1</b>				
$V_{CES}$	$T_j = 25^\circ\text{C}$	1200	V	
$I_C$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	448	A
		$T_c = 80^\circ\text{C}$	341	A
$I_{Cnom}$		350	A	
$I_{CRM}$		700	A	
$V_{GES}$		-20 ... 20	V	
$t_{psc}$	$V_{CC} = 800\text{ V}, V_{GE} \leq 15\text{ V}, T_j = 150^\circ\text{C}, V_{CES} \leq 1200\text{ V}$	8	$\mu\text{s}$	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>IGBT2</b>				
$V_{CES}$	$T_j = 25^\circ\text{C}$	1200	V	
$I_C$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	425	A
		$T_c = 80^\circ\text{C}$	323	A
$I_{Cnom}$		350	A	
$I_{CRM}$		700	A	
$V_{GES}$		-20 ... 20	V	
$t_{psc}$	$V_{CC} = 800\text{ V}, V_{GE} \leq 15\text{ V}, T_j = 150^\circ\text{C}, V_{CES} \leq 1200\text{ V}$	8	$\mu\text{s}$	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>Diode1</b>				
$V_{RRM}$	$T_j = 25^\circ\text{C}$	1200	V	
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	344	A
		$T_c = 80^\circ\text{C}$	257	A
$I_{FRM}$		700	A	
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	1620	A	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>Diode2</b>				
$V_{RRM}$	$T_j = 25^\circ\text{C}$	1200	V	
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	322	A
		$T_c = 80^\circ\text{C}$	239	A
$I_{FRM}$		700	A	
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	1620	A	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>Diode5</b>				
$V_{RRM}$	$T_j = 25^\circ\text{C}$	1200	V	
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	322	A
		$T_c = 80^\circ\text{C}$	239	A
$I_{FRM}$		700	A	
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	1620	A	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>Module</b>				
$I_{t(RMS)}$		340	A	
$T_{stg}$	module without TIM	-40 ... 125	$^\circ\text{C}$	
$V_{isol}$	AC sinus 50Hz, t = 1 min	4000	V	



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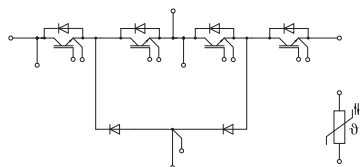
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#### Remarks\*

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
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- IGBT1: outer IGBTs T1 & T4
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#### Footnotes

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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>IGBT1</b>						
$V_{CE(sat)}$	$I_C = 350\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	1.59	1.91		V
		$T_j = 150^\circ\text{C}$	1.85	2.39		V
$V_{CE0}$	chipllevel	$T_j = 25^\circ\text{C}$	0.87	0.94		V
		$T_j = 150^\circ\text{C}$	0.77	0.90		V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	2.1	2.8		m $\Omega$
		$T_j = 150^\circ\text{C}$	3.1	4.3		m $\Omega$
$V_{GE(th)}$	$V_{CE} = 10\text{ V}, I_C = 35\text{ mA}$		5.4	6	6.6	V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 1200\text{ V}, T_j = 25^\circ\text{C}$				3.5	mA
$C_{ies}$	$V_{CE} = 10\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		66.0		nF
$C_{oes}$		$f = 1\text{ MHz}$		2.08		nF
$C_{res}$		$f = 1\text{ MHz}$		0.82		nF
$Q_G$	$V_{GE} = -8\text{ V}\dots+15\text{ V}$			2920		nC
$R_{Gint}$	$T_j = 25^\circ\text{C}$			1.0		$\Omega$
$t_{d(on)}$	$V_{CC} = 600\text{ V}$	$T_j = 150^\circ\text{C}$		181		ns
$t_r$	$I_C = 350\text{ A}$	$T_j = 150^\circ\text{C}$		42		ns
$E_{on}$	$V_{GE} = +15/-8\text{ V}$	$T_j = 150^\circ\text{C}$		13.2		mJ
$t_{d(off)}$	$R_{G on} = 0.5\ \Omega$	$T_j = 150^\circ\text{C}$		389		ns
$t_f$	$R_{G off} = 0.5\ \Omega$	$T_j = 150^\circ\text{C}$		101		ns
$E_{off}$	$di/dt_{on} = 8300\text{ A}/\mu\text{s}$ $di/dt_{off} = 2780\text{ A}/\mu\text{s}$ $dv/dt = 5860\text{ V}/\mu\text{s}$ $L_s = 27\text{ nH}$	$T_j = 150^\circ\text{C}$		37		mJ
$R_{th(j-c)}$	per IGBT				0.114	K/W
$R_{th(c-s)}$	per IGBT ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$ )			0.073		K/W
$R_{th(c-s)}$	per IGBT, pre-applied phase change material			0.033		K/W
<b>IGBT2</b>						
$V_{CE(sat)}$	$I_C = 350\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	1.59	1.91		V
		$T_j = 150^\circ\text{C}$	1.85	2.39		V
$V_{CE0}$	chipllevel	$T_j = 25^\circ\text{C}$	0.87	0.94		V
		$T_j = 150^\circ\text{C}$	0.77	0.90		V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	2.1	2.8		m $\Omega$
		$T_j = 150^\circ\text{C}$	3.1	4.3		m $\Omega$
$V_{GE(th)}$	$V_{CE} = 10\text{ V}, I_C = 35\text{ mA}$		5.4	6	6.6	V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 1200\text{ V}, T_j = 25^\circ\text{C}$				3.5	mA
$C_{ies}$	$V_{CE} = 10\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		66.0		nF
$C_{oes}$		$f = 1\text{ MHz}$		2.08		nF
$C_{res}$		$f = 1\text{ MHz}$		0.82		nF
$Q_G$	$V_{GE} = -8\text{ V}\dots+15\text{ V}$			2920		nC
$R_{Gint}$	$T_j = 25^\circ\text{C}$			1.0		$\Omega$
$t_{d(on)}$	$V_{CC} = 600\text{ V}$	$T_j = 150^\circ\text{C}$		209		ns
$t_r$	$I_C = 350\text{ A}$	$T_j = 150^\circ\text{C}$		50		ns
$E_{on}$	$V_{GE} = +15/-8\text{ V}$	$T_j = 150^\circ\text{C}$		15.4		mJ
$t_{d(off)}$	$R_{G on} = 1\ \Omega$	$T_j = 150^\circ\text{C}$		394		ns
$t_f$	$R_{G off} = 0.5\ \Omega$	$T_j = 150^\circ\text{C}$		108		ns
$E_{off}$	$di/dt_{on} = 7022\text{ A}/\mu\text{s}$ $di/dt_{off} = 2580\text{ A}/\mu\text{s}$ $dv/dt = 5960\text{ V}/\mu\text{s}$ $L_s = 27\text{ nH}$	$T_j = 150^\circ\text{C}$		34.6		mJ
$R_{th(j-c)}$	per IGBT				0.124	K/W
$R_{th(c-s)}$	per IGBT ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$ )			0.076		K/W
$R_{th(c-s)}$	per IGBT, pre-applied phase change material			0.035		K/W



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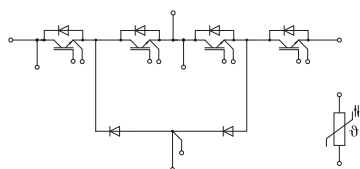
#### Remarks\*

- Case temperature limited to  $T_C=125^{\circ}\text{C}$  max.
- Product reliability results valid for  $T_j \leq 150^{\circ}\text{C}$  (recommended  $T_{j,op} = -40 \dots +150^{\circ}\text{C}$ )
- IGBT1: outer IGBTs T1 & T4
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- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"

#### Footnotes

<sup>1)</sup> Please find further technical information on the SEMIKRON website.

Characteristics		min.	typ.	max.	Unit
Symbol	Conditions				
<b>Diode1</b>					
$V_F = V_{EC}$	$I_F = 350\text{ A}$ $V_{GE} = 0\text{ V}$ chiplevel	$T_j = 25^{\circ}\text{C}$	2.28	2.62	V
		$T_j = 150^{\circ}\text{C}$	2.27	2.59	V
$V_{F0}$	chiplevel	$T_j = 25^{\circ}\text{C}$	1.30	1.50	V
		$T_j = 150^{\circ}\text{C}$	0.90	1.10	V
$r_F$	chiplevel	$T_j = 25^{\circ}\text{C}$	2.8	3.2	m $\Omega$
		$T_j = 150^{\circ}\text{C}$	3.9	4.3	m $\Omega$
$I_{RRM}$	$I_F = 350\text{ A}$	$T_j = 150^{\circ}\text{C}$	306		A
$Q_{rr}$	$di/dt_{off} = 7022\text{ A}/\mu\text{s}$ $V_{CC} = 600\text{ V}$	$T_j = 150^{\circ}\text{C}$	53.7		$\mu\text{C}$
$E_{rr}$	$V_{GE} = +15/-8\text{ V}$	$T_j = 150^{\circ}\text{C}$	26.4		mJ
$R_{th(j-c)}$	per diode			0.18	K/W
$R_{th(c-s)}$	per diode ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^{\circ}\text{K})$ )		0.06		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material		0.047		K/W
<b>Diode2</b>					
$V_F = V_{EC}$	$I_F = 350\text{ A}$ $V_{GE} = 0\text{ V}$ chiplevel	$T_j = 25^{\circ}\text{C}$	2.28	2.62	V
		$T_j = 150^{\circ}\text{C}$	2.27	2.59	V
$V_{F0}$	chiplevel	$T_j = 25^{\circ}\text{C}$	1.30	1.50	V
		$T_j = 150^{\circ}\text{C}$	0.90	1.10	V
$r_F$	chiplevel	$T_j = 25^{\circ}\text{C}$	2.8	3.2	m $\Omega$
		$T_j = 150^{\circ}\text{C}$	3.9	4.3	m $\Omega$
$I_{RRM}$	$I_F = 350\text{ A}$	$T_j = 150^{\circ}\text{C}$	306		A
$Q_{rr}$	$di/dt_{off} = 6000\text{ A}/\mu\text{s}$ $V_R = 600\text{ V}$	$T_j = 150^{\circ}\text{C}$	46		$\mu\text{C}$
$E_{rr} \text{ } ^1)$	$V_{GE} = +15/-8\text{ V}$	$T_j = 150^{\circ}\text{C}$	-		mJ
$R_{th(j-c)}$	per diode			0.2	K/W
$R_{th(c-s)}$	per diode ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^{\circ}\text{K})$ )		0.06		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material		0.033		K/W
<b>Diode5</b>					
$V_F = V_{EC}$	$I_F = 350\text{ A}$ chiplevel	$T_j = 25^{\circ}\text{C}$	2.28	2.62	V
		$T_j = 150^{\circ}\text{C}$	2.27	2.59	V
$V_{F0}$	chiplevel	$T_j = 25^{\circ}\text{C}$	1.30	1.50	V
		$T_j = 150^{\circ}\text{C}$	0.90	1.10	V
$r_F$	chiplevel	$T_j = 25^{\circ}\text{C}$	2.8	3.2	m $\Omega$
		$T_j = 150^{\circ}\text{C}$	3.9	4.3	m $\Omega$
$I_{RRM}$	$I_F = 350\text{ A}$	$T_j = 150^{\circ}\text{C}$	407		A
$Q_{rr}$	$di/dt_{off} = 8300\text{ A}/\mu\text{s}$ $V_R = 600\text{ V}$	$T_j = 150^{\circ}\text{C}$	52		$\mu\text{C}$
$E_{rr}$	$V_{GE} = +15/-8\text{ V}$	$T_j = 150^{\circ}\text{C}$	26		mJ
$R_{th(j-c)}$	per diode			0.2	K/W
$R_{th(c-s)}$	per diode ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^{\circ}\text{K})$ )		0.07		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material		0.052		K/W



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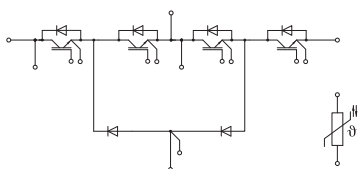
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Module</b>						
$L_{sCE1}$				27		nH
$L_{sCE2}$				34		nH
$R_{CC'+EE'}$	measured between terminal 5 and 1	$T_C = 25^\circ\text{C}$		0.27		m $\Omega$
		$T_C = 125^\circ\text{C}$		0.72		m $\Omega$
$R_{th(c-s)1}$	calculated without thermal coupling			0.007		K/W
$R_{th(c-s)2}$	including thermal coupling, $T_s$ underneath module ( $\lambda_{grease}=0.81 \text{ W}/(\text{m}^2\text{K})$ )			0.013		K/W
$R_{th(c-s)2}$	including thermal coupling, $T_s$ underneath module, pre-applied phase change material			0.006		K/W
$M_s$	to heat sink (M5)		3		6	Nm
$M_t$		to terminals (M6)	3		6	Nm
						Nm
$W$				398		g
<b>Temperature Sensor</b>						
$R_{100}$	$T_C=100^\circ\text{C}$ ( $R_{25}=5 \text{ k}\Omega$ )			$493 \pm 5\%$		$\Omega$
$B_{100/125}$	$R_{(T)}=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$ ; $T[\text{K}]$ ;			$3550 \pm 2\%$		K



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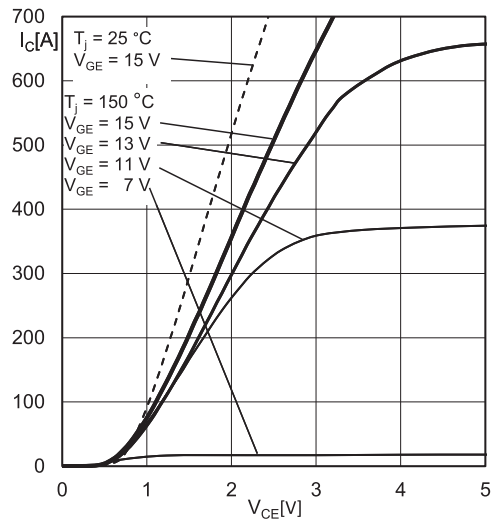


Fig. 1: Typ. IGBT1 output characteristic, incl.  $R_{CC'+EE'}$

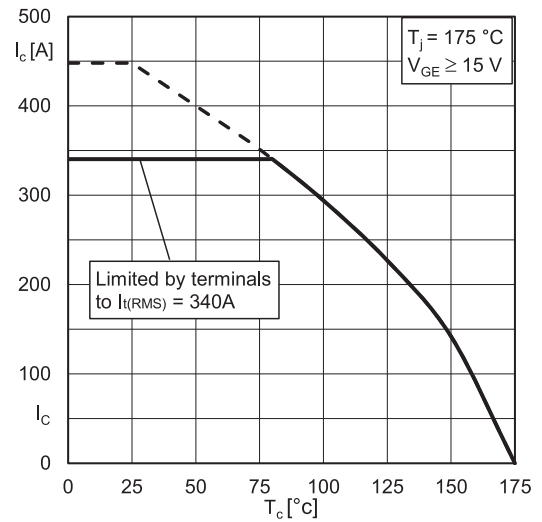


Fig. 2: IGBT1 rated current vs. Temperature  $I_c=f(T_c)$

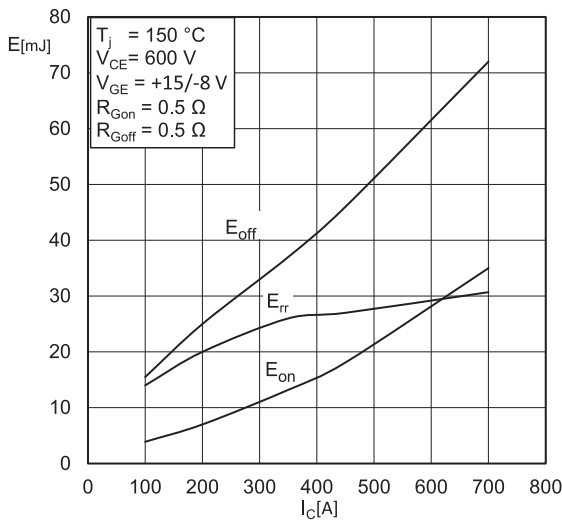


Fig. 3: Typ. IGBT1 & Diode5 turn-on /-off energy =  $f(I_c)$

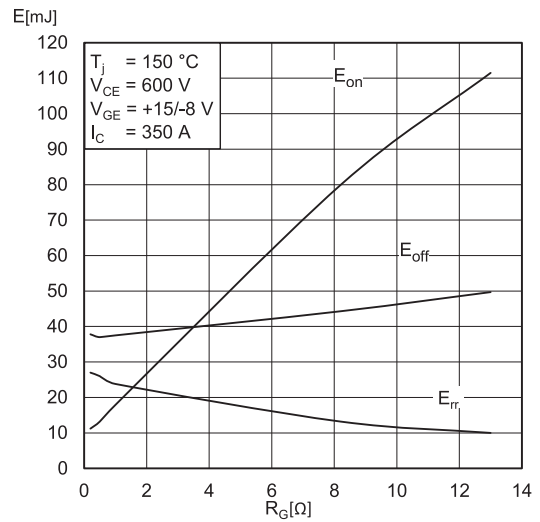


Fig. 4: Typ. IGBT1 & Diode5 turn-on /-off energy =  $f(R_G)$

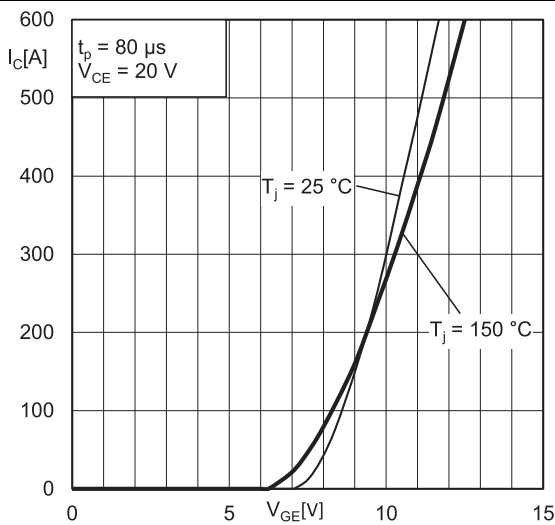


Fig. 5: Typ. IGBT1 transfer characteristic

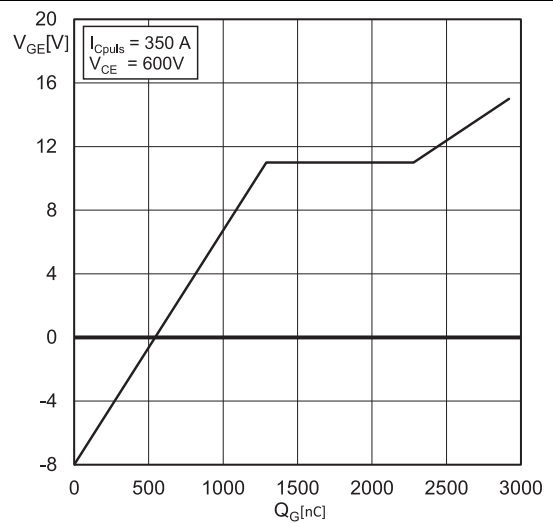


Fig. 6: Typ. IGBT1 gate charge characteristic

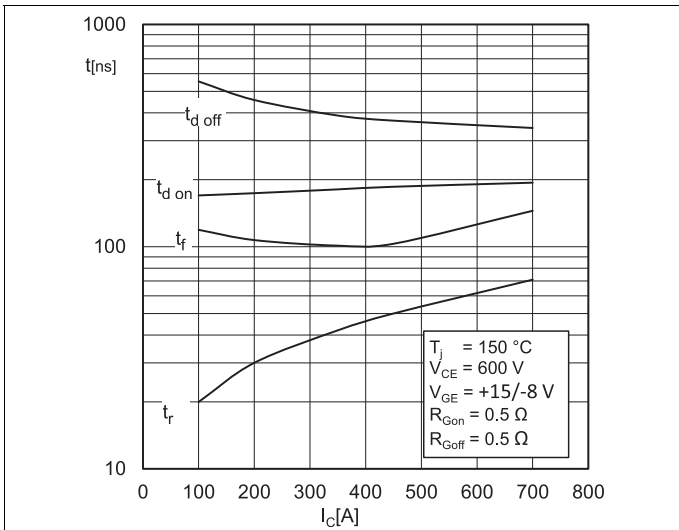


Fig. 7: Typ. IGBT1 switching times vs.  $I_c$

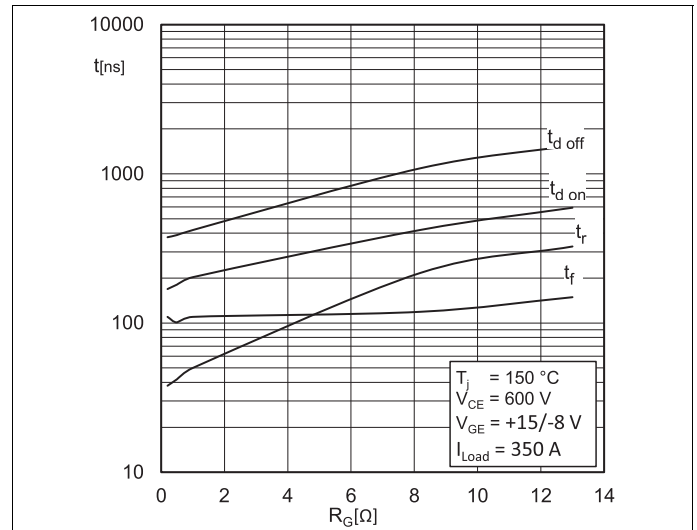


Fig. 8: Typ. IGBT1 switching times vs. gate resistor  $R_G$

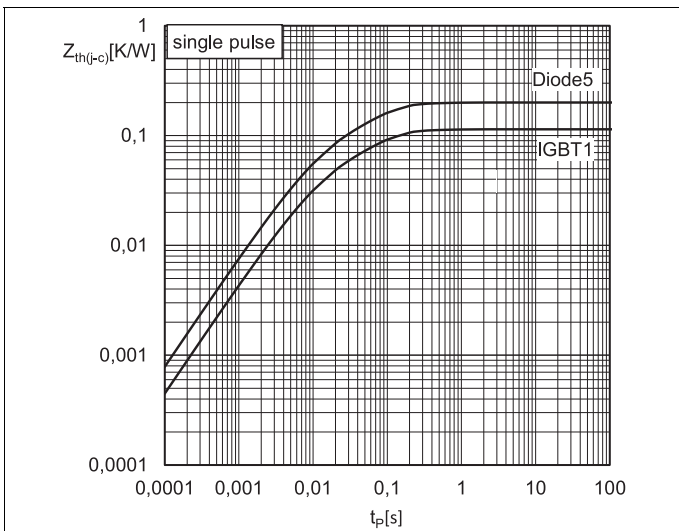


Fig. 9: Typ. transient thermal impedance of IGBT1 & Diode5

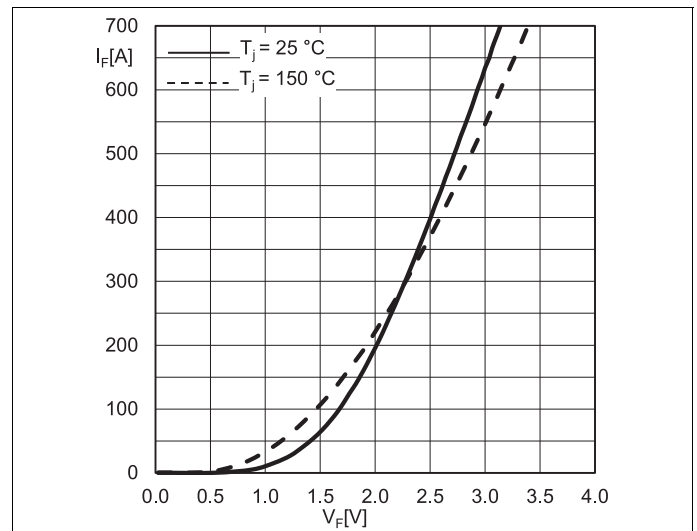


Fig. 10: Typ. Diode5 forward characteristic, incl.  $R_{CC+EE'}$

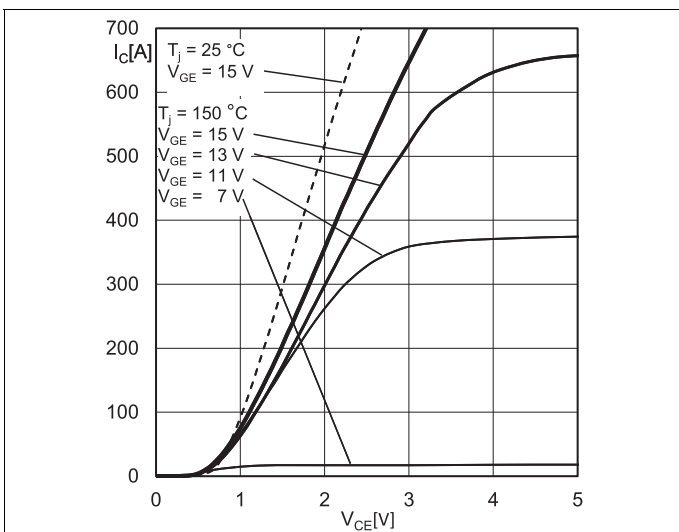


Fig. 13: Typ. IGBT2 output characteristic, incl.  $R_{CC+EE'}$

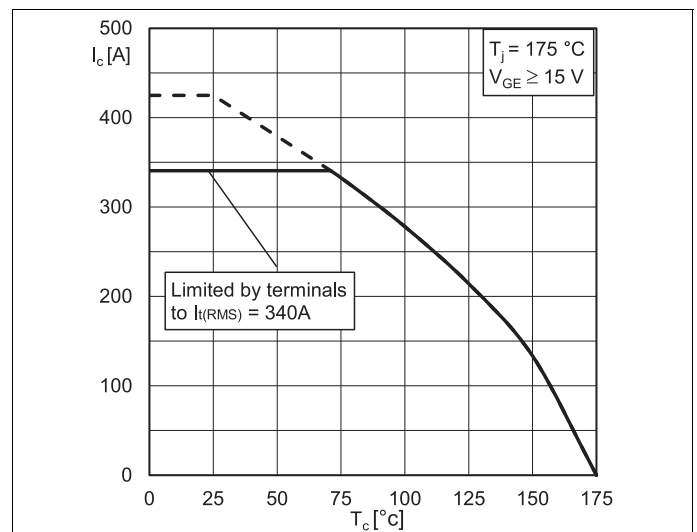


Fig. 14: IGBT2 rated current vs. Temperature  $I_c = f(T_c)$

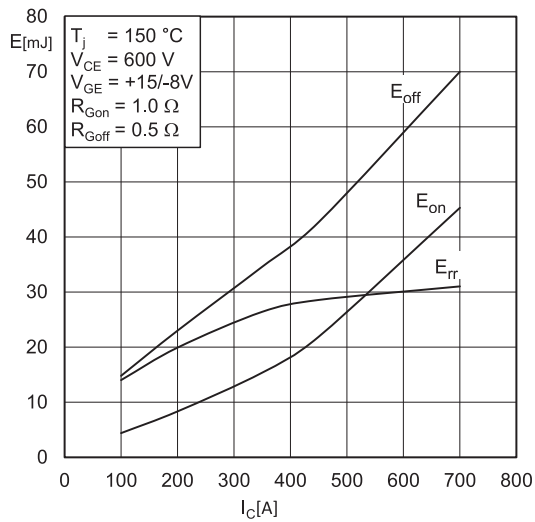


Fig. 15: Typ. IGBT2 & Diode1 turn-on /-off energy =  $f(I_C)$

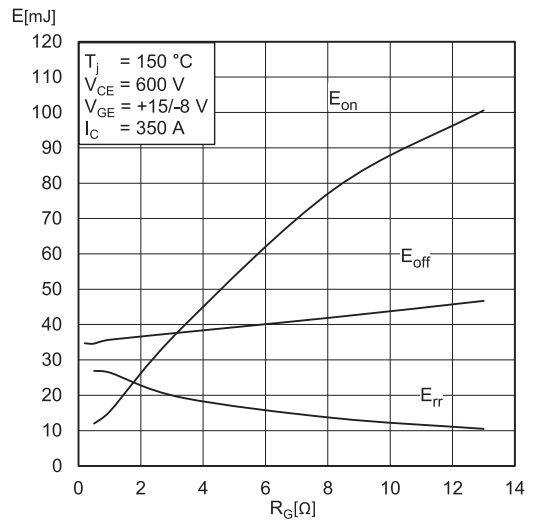


Fig. 16: Typ. IGBT2 & Diode1 turn-on / -off energy =  $f(R_G)$

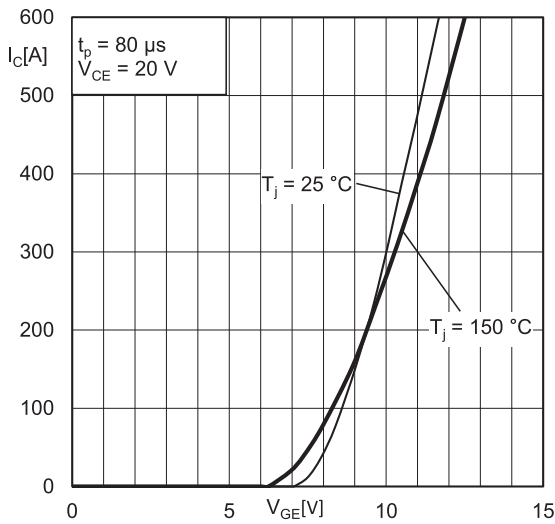


Fig. 17: Typ. IGBT2 transfer characteristic

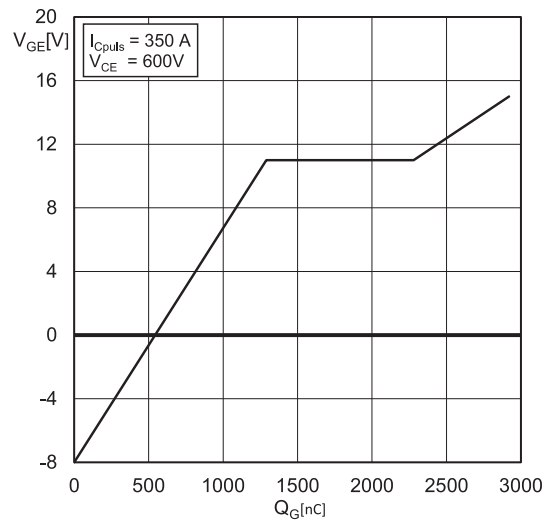


Fig. 18: Typ. IGBT2 gate charge characteristic

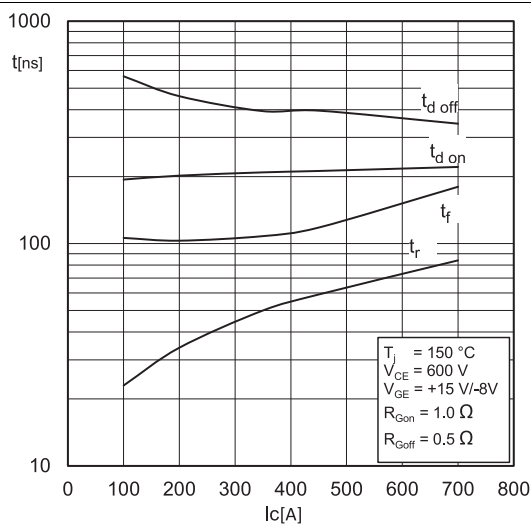


Fig. 19: Typ. IGBT2 switching times vs.  $I_C$

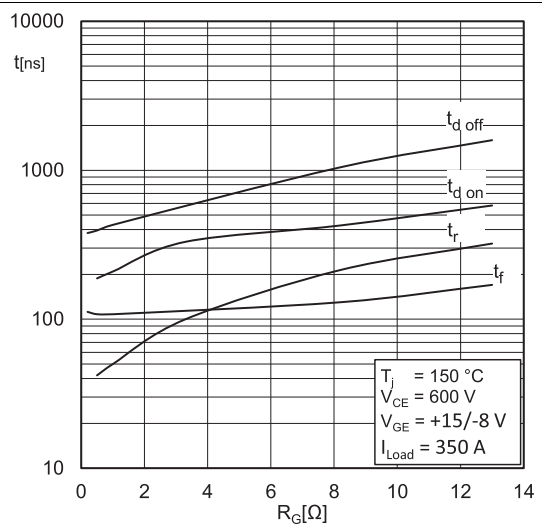


Fig. 20: Typ. IGBT2 switching times vs. gate resistor  $R_G$

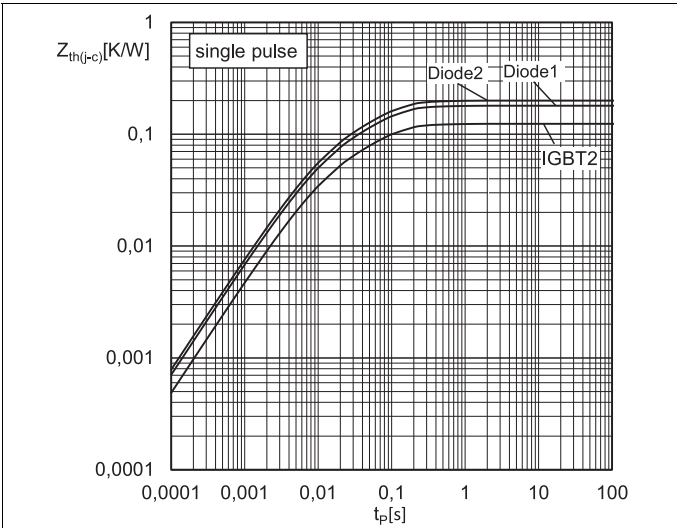


Fig. 21: Transient thermal impedance of IGBT2, Diode1 & Diode2

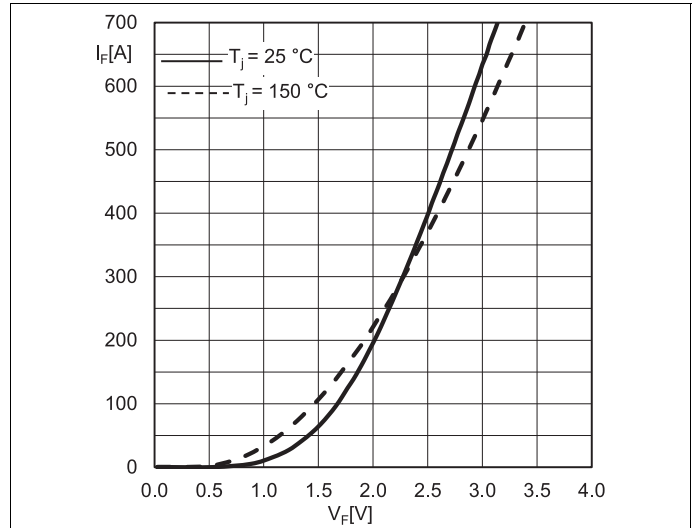
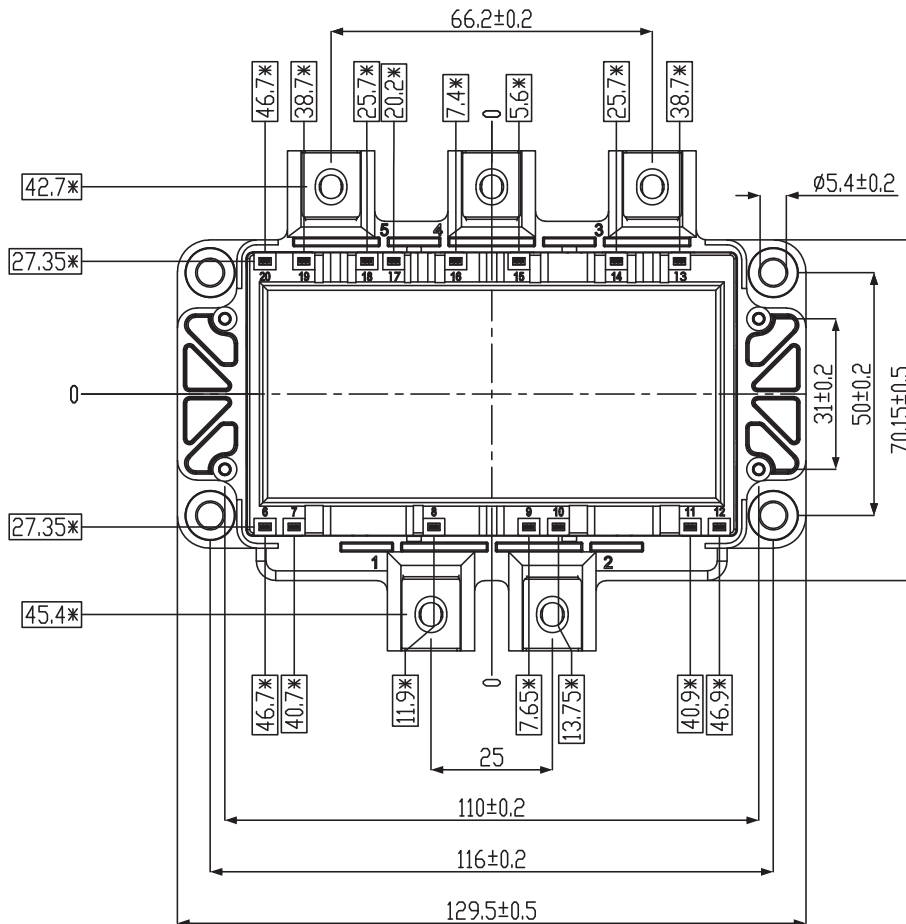
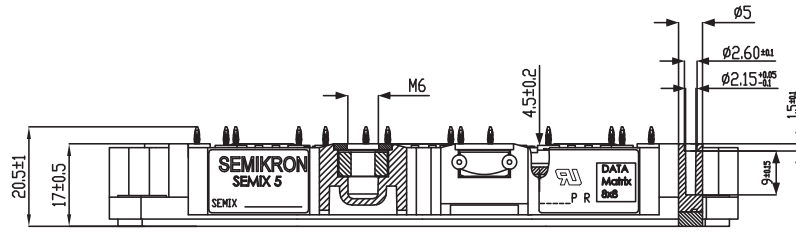


Fig. 22: Typ. Diode1 & Diode2 forward characteristic, incl.  $R_{CC+EE}$



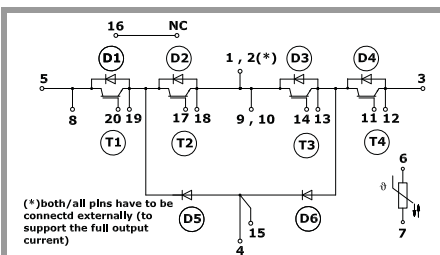
# SEMiX355MLI12M7



\* = Dimensions in mm with tolerance of  $\pm 0.4$

For technical details please refer to SEMiX(R)5 Mounting Instruction

SEMiX5p



MLI

This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

## **\*IMPORTANT INFORMATION AND WARNINGS**

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